FUJITSU MICROELECTRONICS

MOS 4096-BIT STATIC RANDOM ACCESS MEMORY

MBM2149-45 MBM2149-55L MBM2149-70L

DESCRIPTION

The Fujitsu MBM2149 is a 1024 word by 4-bit static random access memory fabricated using N-channel silicon gate MOS technology. The memory is fully static and requires no clock or timing strobe. All pins are TTL compatible and a single 5V power supply is required.

A separate chip select (CS) pin simplifies multipackage systems design by permitting the selection of an individual package when outputs are OR-tied. Fujitsu's MBM2149 offers the advantages of low power dissipation, low cost and high performance.

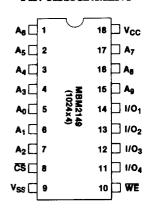
FEATURES

- Organization: 1024 words x 4 bits
- Static operation; no clocks or timing strobe required
- Address Access Time: MBM2149-45: 45 ns max. MBM2149-55L: 55 ns max. MBM2149-70L: 70 ns max.
- Chip Select Access Time: MBM2149-45: 20 ns max. MBM2149-55L: 25 ns max. MBM2149-70L: 30 ns max.
- Low Power Consumption: MBM2149-45: 180mA MBM2149-55L/-70L: 125mA

- Single +5V DC supply voltage (±10% tolerance)
- · Common data Input/output
- TTL compatible inputs/outputs
- Three-state output with OR-tie capability
- Chip select for simplified memory expansion
- Standard 18-pin DIP package
- Pin compatible with Intel 2149

CERDIP PACKAGE DIP-18C-C01

PIN ASSIGNMENT

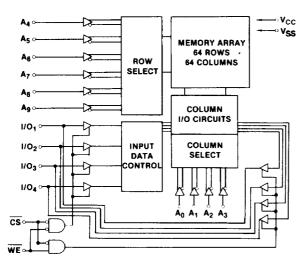


TRUTH TABLE

<u>cs</u>	WE	Mode	1/0		
Н	Х	Not Selected	High Z		
L	L	www.Data	Short4U.		
L	Н	Read	DOUT		

olim.

MBM2149 BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS (See Note)

Rating	Symbol	Value	Unit	
Voltage On Any Pin with respect to V _{SS}	VIN, VOUT, VCC	-3.5 to +7	V	
Short Circuit Output Current		20	mA_	
Temperature Under Bias	TA	-10 to +85	•c	
	T _{sta}	-65 to +150	c	
Storage Temperature	PD	1.2	W	
Power Dissipation				

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to the conditions as detailed in the operations sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. It is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high Impedance circuit.

CAPACITANCE(1)

 $(T_A = 25 \,{}^{\circ}C; f = 1 \,MHz)$

Parameter	Symbol	Тур	Max	Unit
Address/Control Capacitance (V _{IN} = 0V)	C _{IN}	_	5	pF
Input/Output Capacitance (V _{I/O} = 0V)	C _{I/O}		7	pF

NOTE: 1. This parameter is sampled and not 100% tested.

RECOMMENDED OPERATING CONDITIONS

(Referenced to VSS)

Parameter	Symbol	Min	Тур	Max	Unit	Ambient ⁽¹⁾ Temperature
Supply Voltage	V _{CC}	4.5	5.0	5.5	V	
Input Low Voltage	V _{IL}	-3.0		0.8		0°C to +70°C
Input High Voltage	VIH	2.1		6.0		

NOTE: 1. The operating ambient temperature range is guaranteed with transverse airflow exceeding 400 linear feet per minute.

DC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted)

Parameter	Leakage Current = V _{SS} to V _{CC} , V _{CC} = Max) /Output Leakage Current = V _{IH} , V _{I/O} = V _{SS} to 4.5V, V _{CC} = Max) er Supply Current MBM2149-45				Max	Unit
Input Leakage Current (VIN = VSS to VCC, VCC = Max)			ILI	-10	10	μΑ
Input/Output Leakage Current	Max)		lLO	-50	50	μΑ
Power Supply Current	MBM2149-45		lcc		180	mA
$(V_{CC} = Max, \overline{CS} = V_{II}, I_{OUT} = 0mA)$	MBM2149-55L	-70L	Icc		(125	mA
Output Low Voltage (IoL = 8mA)			V _{OL}	I –	0.4	V
Output High Voltage (I _{OH} = -4mA)		V _{OH}	2.4	www.Data	Shee\4U.c	
Output Short Circuit Current (VOUT = Vss to VCC)			los	<u> </u>	±200	mA

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AC CHARACTERISTICS

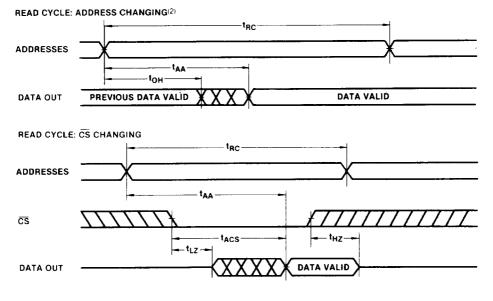
(Recommended Operating Conditions unless otherwise noted.)

READ CYCLE

	ME		MBM2	MBM2149-45 MI		MBM2149-55L		MBM2149-70L	
Parameter	NOTES Symb	Symbol	Min	Max	Min	Max	Min	Max	Unit
Read Cycle Time		tRC	45	-	55		70		ns
Address Access Time		t _{AA}	-	(45)) -	<u>(55)</u>		(70)	ns
Chip Select Access Time		tACS		(20)) —	25	? —	30) ns
Previous Read Data Valid After Change of Address		tон	5	_	5	Ī	5	_	пѕ
Chip Select to Output Active	1	tLZ	5	-	5		5		ns
Chip Select to Output Three-State	e 1	tHZ	0	15	0	15	0	15	ns

NOTE: 1. Transition is measured ±500 mV from high impedance voltage with LOAD B. This parameter is sampled and not 100% tested.

READ CYCLE (1)



Note: 1. WE is high for Read Cycle.

2. Device is continuously selected, $\overline{CS} = V_{1L}$.

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MBM2149

AC CHARACTERISTICS

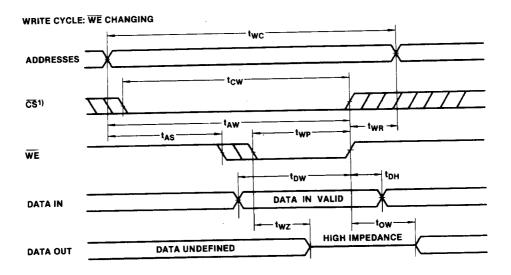
(Recommended operating conditions unless otherwise noted.)

WRITE CYCLE

		MBM2	149-45	MBM2	149-55L	MBM2	149-70L	Unit	
Parameter <u>l</u>	OTES	Symbol	Min	Max	Min	Max	Min	Max	
Maile Cycle Time		twc	45		55	_	70		ns
Write Cycle Time		taw	40		50	_	65		ns
Address Valid to End of Write		tcw	40		50	_	65	_	ns
Chip Select to End of Write			20	<u> </u>	20		25	_	ns
Data Valid to End of Write		1 _{DW} _	0		0		0		ns
Data Hold Time		t _{DH}	35	 	40		50		ns
Write Pulse Width		t _{WP}		<u> </u>	5	 	5	_	ns
Write Recovery Time		twn	5		0		1 0	 	ns
Address Setup Time		tas	0	<u> </u>	<u> </u>	 	1 0	 	ns
Output Active From End of Write	1	tow	0		0_	- -		25	ns
Write Enabled to Output Three-Si		t _{WZ}	0	15	0	20	0	23	

NOTE: 1. Transition is measured ±500 mV from high impedance voltage with LOAD B. This parameter is sampled and not 100% tested.

WRITE CYCLE

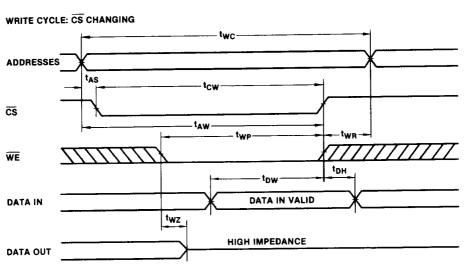


NOTE: 1. If $\overline{\text{CS}}$ goes high simulataneously with $\overline{\text{WE}}$ high, the output remains in a high impedance state.

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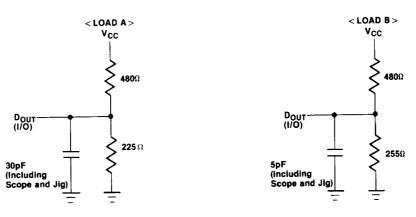
WRITE CYCLE



AC TEST CONDITIONS

Input Pulse Level: 0V to 3.0V Input Pulse Rise and Fall Times: 5ns

Timing Measurement Reference Levels: Inputs: 1.5V Outputs: 1.5V



OVERVIEW

The MBM2149 family from Fujitsu are high performance parts. They are designed for high speed and low power system requirements. The high speed is obtained by advanced NMOS processing.

Input and data bus lines are an area of concern. Unless bus lines are properly designed and terminated, cross coupling, cross talk and reflections can occur. Of particular importance is the undershoot on address line. Careful attention to good PC board layout and proper termination techniques will yield a well designed and reliable memory system.